Evaluation of the electroanalytical performance of carbon-on-gold films prepared by electron-beam evaporation

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Figure S1. Raman spectrum of eC/Au (514.5 nm, 30 mW, 100 s, 50x). Breit-Wigner-Fano (BWF) and Lorentzian fittings for D and G bands respectively results in excellent deconvolution with low residuals as suggested by Ferrari and Robertson.¹ The relative positions of D (1372 cm⁻¹) and G (1559 cm⁻¹) bands were used to estimate sp³ content.¹



Figure S2. XPS survey spectrum of freshly prepared eC/Au.



Figure S3. XPS C1s high resolution spectrum of freshly prepared eC/Au. The C1s peak can be decomposed into 4 components. The peaks at 284.3 eV and 285.3 eV are assigned to sp^2 and sp^3 hybrids, respectively.²



Figure S4. (A) AFM images of Si/Cr₂/Au₄₂ (Au) and Si/Cr₂/Au₄₂/eC₁₀ (eC/Au) films (the subscripts indicate thicknesses in nm). (B) AFM line scan profiles of the surfaces shown in panel A.



Figure S5. Background voltammograms of eC/Au and polished GC in $H_2SO_4 0.05 \text{ M}$, v = 0.1 V/s. The current is normalized to the electrode area to give current density. The black arrow indicates the scan direction.



Figure S6. Scan rate dependent background current for eC/Au in 1 M KCl. The black arrow indicates the scan direction.



Figure S7. Scan rate dependent background current for eC/Au in 1 M HClO₄. The black arrow indicates the scan direction.



Figure S8. Representative plot of $\Delta E_{p,obs}$ vs. cathodic peak current from cyclic voltammetry of $Fe(CN)_6^{3-}$ (1 M KCl, v = 0.1 V/s) at an eC/Au film. The concentration of $Fe(CN)_6^{3-}$ was varied from 1 to 16 mM to affect the different peak currents. The slope of each least-squares, linear fit yields $2R_u$.

The effects of electrode resistance on electron transfer kinetics at pyrolyzed photoresist films (PPF) were observed in a report by Ranganathan et al.³ Specifically, ΔE_p of Fe(CN)₆^{3-/4-} and Ru(NH₃)₆^{3+/2+} increased with higher concentrations, implying a significant contribution from the iR drop in the PPF electrode due to its thinness. In a later report,⁴ they noted that the resistance within the PPF increases the observed peak separation according to

$$\Delta E_{p,corrected} = \Delta E_{p,observed} - 2 |i| R_u$$
(1)

where i the peak current in amperes, R_u is the uncompensated cell resistance in ohms, $\Delta E_{p,observed}$ is the observed ΔE_p in the presence of the uncompensated cell resistance in volts, and $\Delta E_{p,corrected}$ is the corrected ΔE_p in volts.

Rearranging eq. (1), we obtain

 $\Delta E_{p,observed} = 2 |i| R_u + \Delta E_{p,corrected}$

In our previous work,⁵ we reported that a plot of $\Delta E_{p,observed}$ vs. i from voltammograms at a

common scan rate would yield a linear relationship, in which the slope of the fit equals to 2R_u.

The concentrations of Fe(CN) $_{6}^{3-}$ can be varied to affect the different peak currents. Since $i_{pc}/i_{pa} \sim$

1 for $Fe(CN)_{6^{3-}}$ at eC/Au electrodes, either i_{pc} or i_{pa} can be used in the calculations.

References

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